

FORM PTO-1449
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)



Atty Docket No. : 12177/13401
Serial No. : 09/557,672
Inventors : Michael K. BRAND et al.
Filed : April 25, 2000
Group Art Unit : 2128
Examiner : Thai Q. PHAN

U.S. PATENT DOCUMENTS

<u>Examiner Initial</u>	<u>Patent Number</u>	<u>Issue Date</u>	<u>Inventor(s)</u>
<u>KK</u>	6,816,813	11-2004	Tan et al.
<u>KK</u>	6,684,349	1-2004	Gullo et al.
<u>KK</u>	5,210,704	5-1993	Husseiny, Abdo A.
<u>KK</u>	5,648,919	7-1997	Yamauchi et al.
<u>KK</u>	5,789,682	8-1998	Dickinson et al.
<u>KK</u>	5,949,682	9-1999	Dickinson et al.
<u>KK</u>	6,301,970	10-2001	Biggs et al.

OTHER DOCUMENTS

Examiner
Initial

KK

Analog Device's Reliability Handbook. pp. 1-23 out of 88 pages.
copyright 2000.

KK

Military Standard MIL-STD-690C. March 26, 1993.

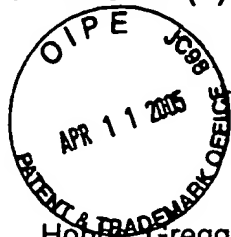

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KK

Hobbs, Gregg. "What HALT and HASS Can Do For Your Products".
copyright 1997, Nelson Publishing

KK

Wiesling, Paul. "Advance Program 1st IEEE/CPMT 2-day Workshop
on Accelerated Stress Testing, Sept. 7-8, 1995" Aug. 28, 1995.

KK

Linear Technology, "Reliability Assurance Program", especially p.
11. Undated. www.linear.com/company/quality/RAPweb.pdf.
Printed by Examiner on 12/27/04.

KK

McLean, Harry. "A Statistical Approach for the Disposition of HALT
Issues." Feb. 15, 2001.

KK

Prakash, Simon. "The Application of HALT and HASS Principles in
a High Volume Manufacturing Environment." Qual. Reliab. Engng.
Int., Vol. 14, pp. 385-392, copyright 1998.

KK

Confer, R. et al. "Use of Highly Accelerated Life Test (HALT) to
Determine Reliability of Multilayer Ceramic Capacitors." Proc. 41st
Electronic Components and Technology Conf., 1991. pp. 320-322

KK

Gera, A. E. "The Modified Exponentiated Weibull Distribution for
Life-Time Modeling." Proc. Annual Reliability and Maintainability
Symposium, Jan. 16, 1997. pp. 149-152.

KK

Kim, J.S. "A Test of the Exponential MTBF and Comparison of
Power Functions of the Random Censoring Case." IEEE
Transactions on Reliability. April 1988. pp. 103-107.


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KK

Mudholkar, G.S. et al. "Exponentiated Weibull Family for Analyzing Bathtub Failure-Rate Data." IEEE Transactions on Reliability. June 1993. pp. 299-302. *(copy not provided by examiner)*

KK

Upadhyayula, K. et al. "Guidelines for Physics-of-Failure Based Accelerated Stress Testing." Proc. Annual Reliability and Maintainability Symposium. Jan. 22, 1998. pp. 345-357. *(copy not provided by examiner)*

KK

Scalise, J. "Plastic Encapsulated Microcircuits (PEM) Qualification Testing." 46th Electronic Components and Technology Conference, 1996. May 31, 1996. pp. 392-397.

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